

A 5GHz, 1mW CMOS Voltage–Controlled Differential Injection–Locked Frequency Divider

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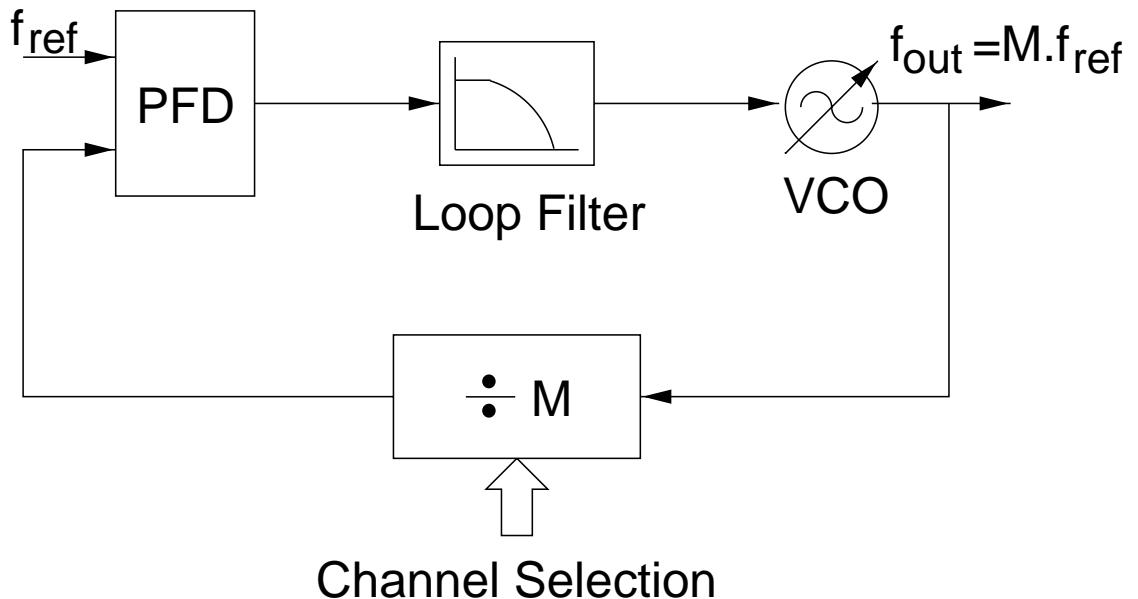
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OUTLINE

- motivation
- injection-locked frequency dividers (ILFDs)
 - mathematical model
 - circuit implementation
 - design issues
 - * optimal inductor design
- measurement results
- summary
- conclusion

MOTIVATION

- wireless systems:
 - are narrowband
 - require frequency synthesizers
 - require low power operation
- PLL-based frequency synthesizer require frequency dividers
- conventional dividers:
 - wideband
 - power hungry



IDEA

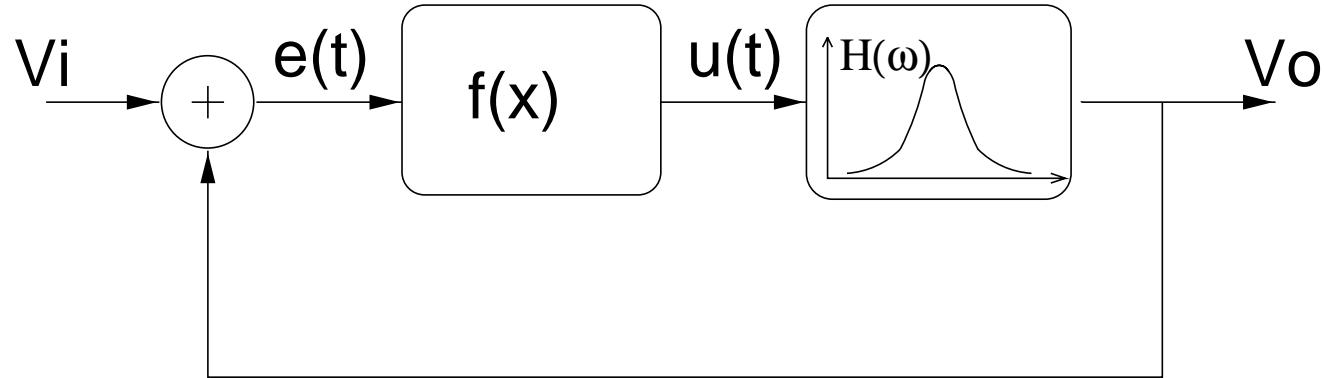
- design a low-power and narrowband frequency divider

use resonators to trade off bandwidth for power

INJECTION-LOCKED OSCILLATORS

- by impressing an oscillator with an external (incident) signal, frequency locking can be achieved
 - first-harmonic injection locked oscillators ($f_i = f_o$)
 - subharmonic injection locked oscillators ($f_i = \frac{1}{N}f_o$)
 - superharmonic injection locked oscillators ($f_i = N \times f_o$)
 - injection-locked frequency dividers (ILFDs)

ILFD MODEL



$$v_o(t) = V_o \cos(\omega_o t)$$

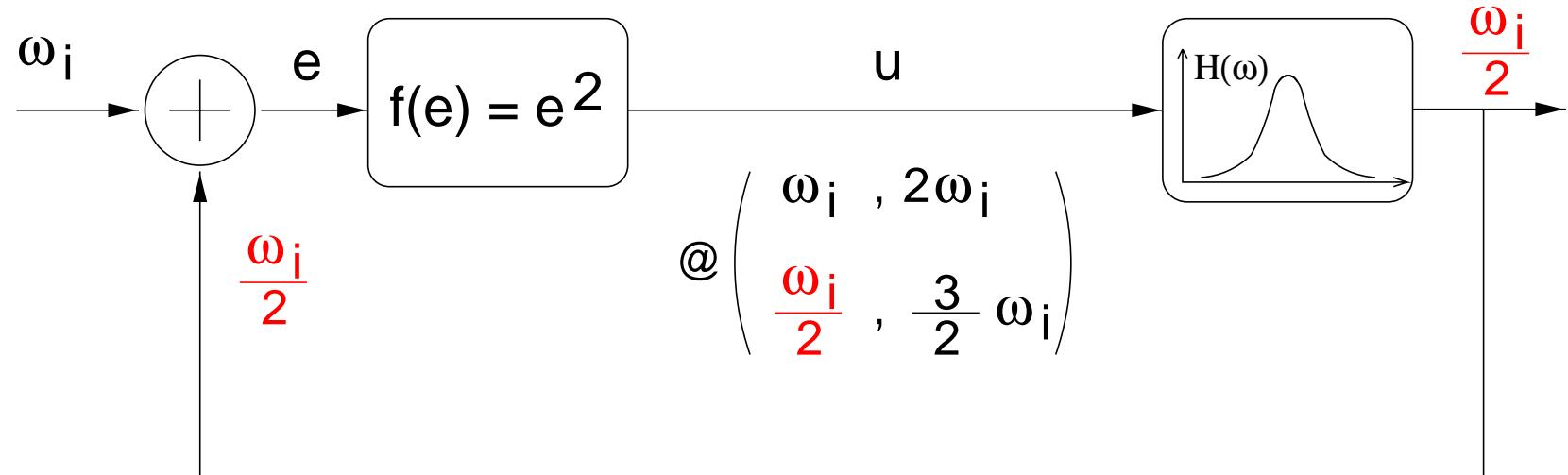
$$v_i(t) = V_i \cos(\omega_i t + \phi)$$

$$u(t) = f[e(t)] = f[v_o(t) + v_i(t)]$$

$$H(\omega) = \frac{H_0}{1 + j2Q\frac{\omega - \omega_r}{\omega_r}}$$

- oscillation condition should be satisfied in the presence of the incident signal.

SIMPLIFIED PICTURE



$$e = \cos(\omega_i t) + \cos\left(\frac{\omega_i}{2}t\right)$$

$$u = [\cos(\omega_i t) + \cos\left(\frac{\omega_i}{2}t\right)]^2$$

$$u = 1 + \frac{1}{2}\cos(2\omega_i t) + \frac{1}{2}\cos(\omega_i t) + \cos\left(\frac{3\omega_i}{2}t\right) + \cos\left(\frac{\omega_i}{2}t\right)$$

SPECIAL CASE (DIVIDE-BY-TWO)

$$f(e) = a_0 + a_1 e + a_2 e^2 + a_3 e^3$$

- phase condition:

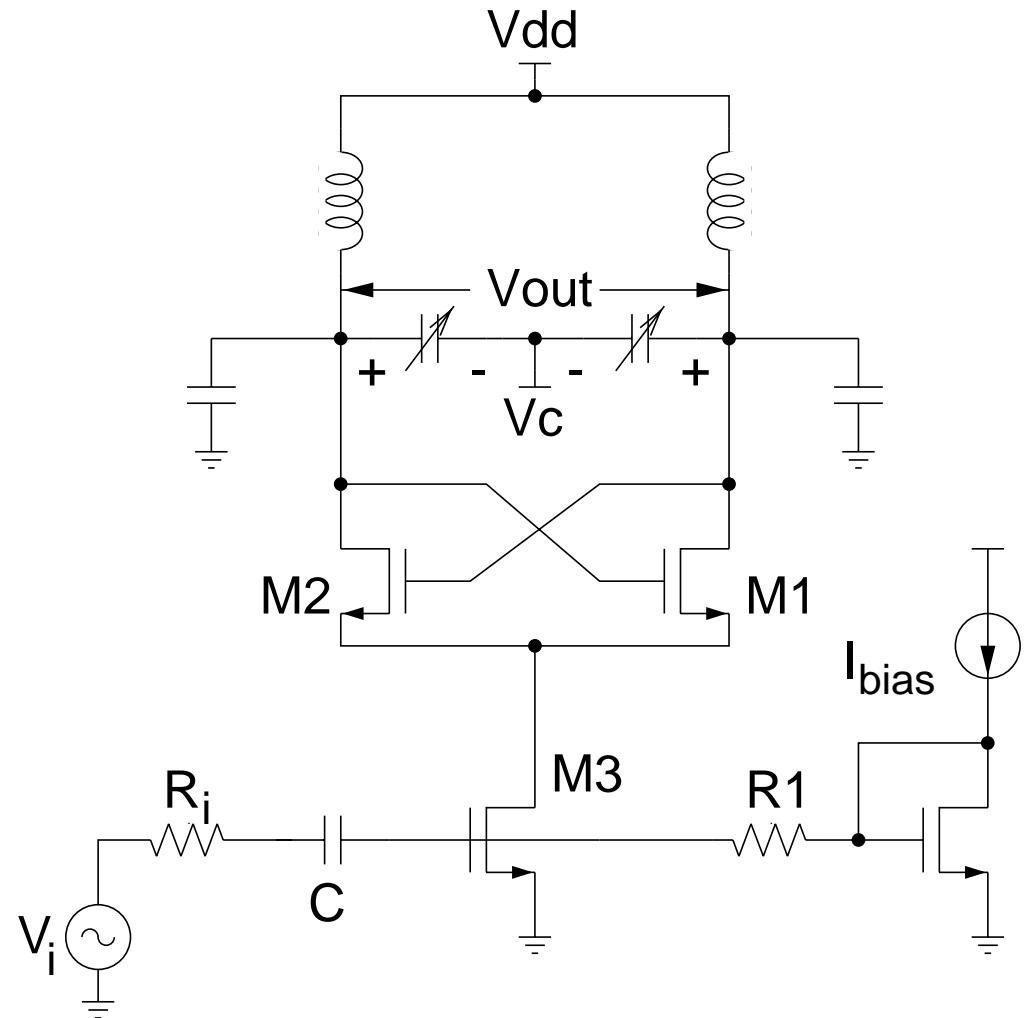
$$\left| \frac{\Delta\omega}{\omega_r} \right| < \left| \frac{H_0 a_2 V_i}{2Q} \right| \quad , \quad \frac{H_0}{Q} = \frac{LQ\omega_r}{Q} = L\omega_r$$

- gain condition:

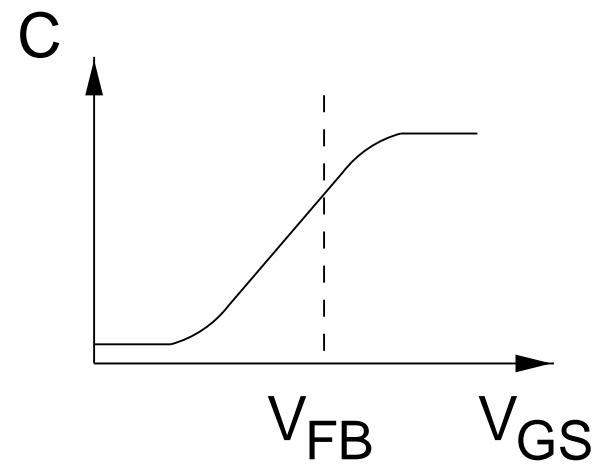
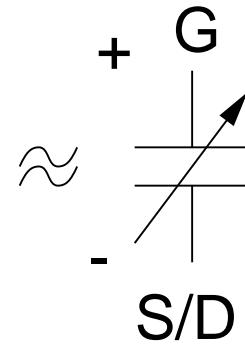
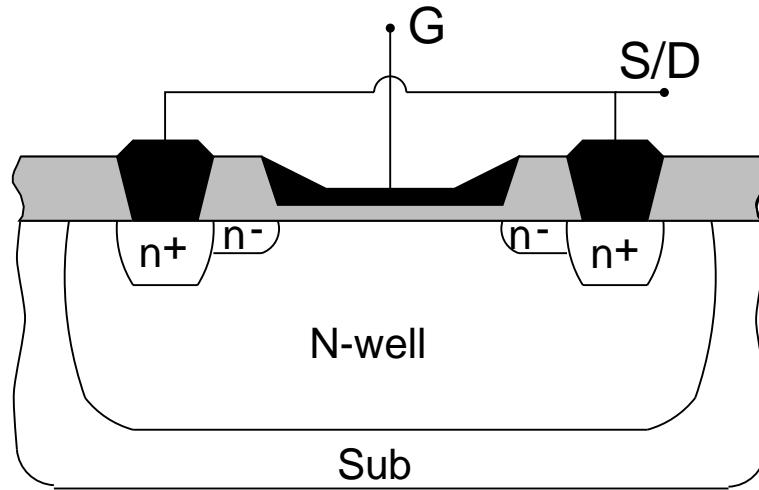
$$H_0 \left(a_1 + \frac{3}{2} a_3 V_i^2 + a_2 V_i \cos(\phi) \right) < 1$$

VOLTAGE-CONTROLLED DIFFERENTIAL ILFD

- $0.24\mu\text{m}$ CMOS
- $V_{dd}=1.5\text{V}$
- $I_{bias}=300\mu\text{A}$
- $f_o=2.25\text{GHz}$
- $f_i=4.5\text{GHz}$



VARACTOR

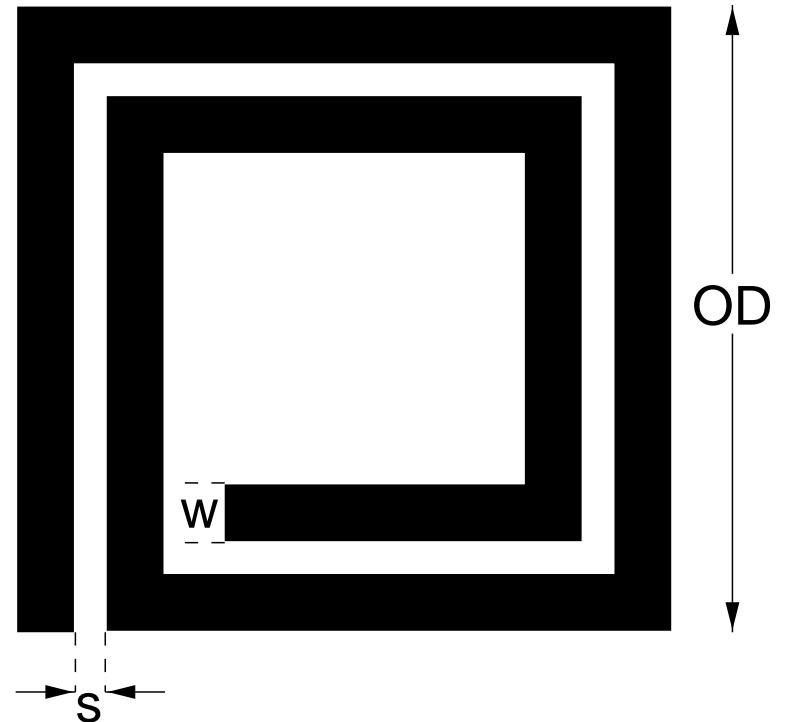
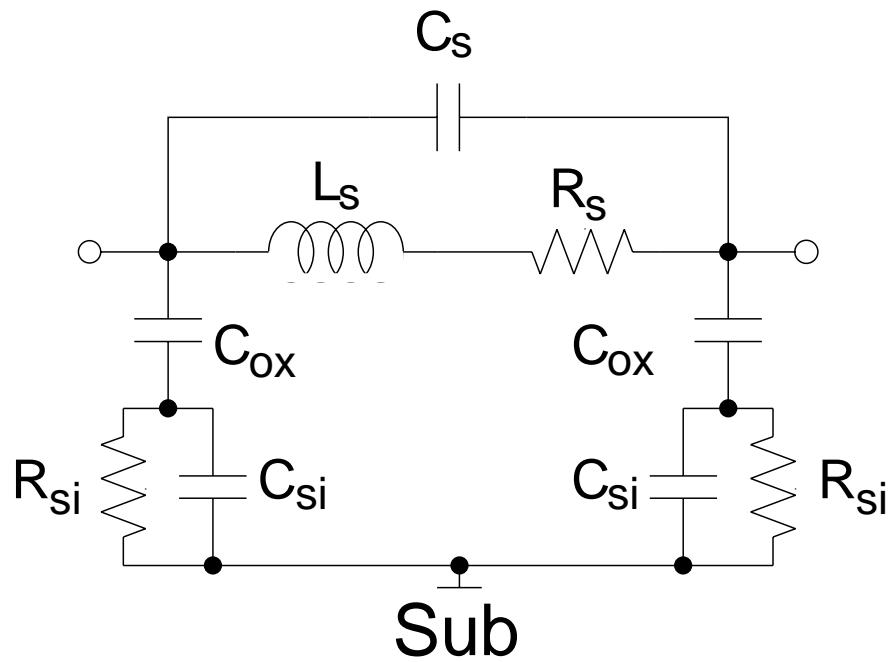


- accumulation mode MOS capacitor
 - large quality factor (> 60 @ 2.5GHz)
 - flat-band voltage \approx zero volt

INDUCTOR DESIGN

- maximum locking range \Rightarrow maximize L
- minimum power consumption \Rightarrow maximize LQ

INDUCTOR DESIGN



- design parameters:
 - w : metal width
 - s : metal spacing
 - OD: outer dimension
 - n : number of turns

INDUCTOR DESIGN

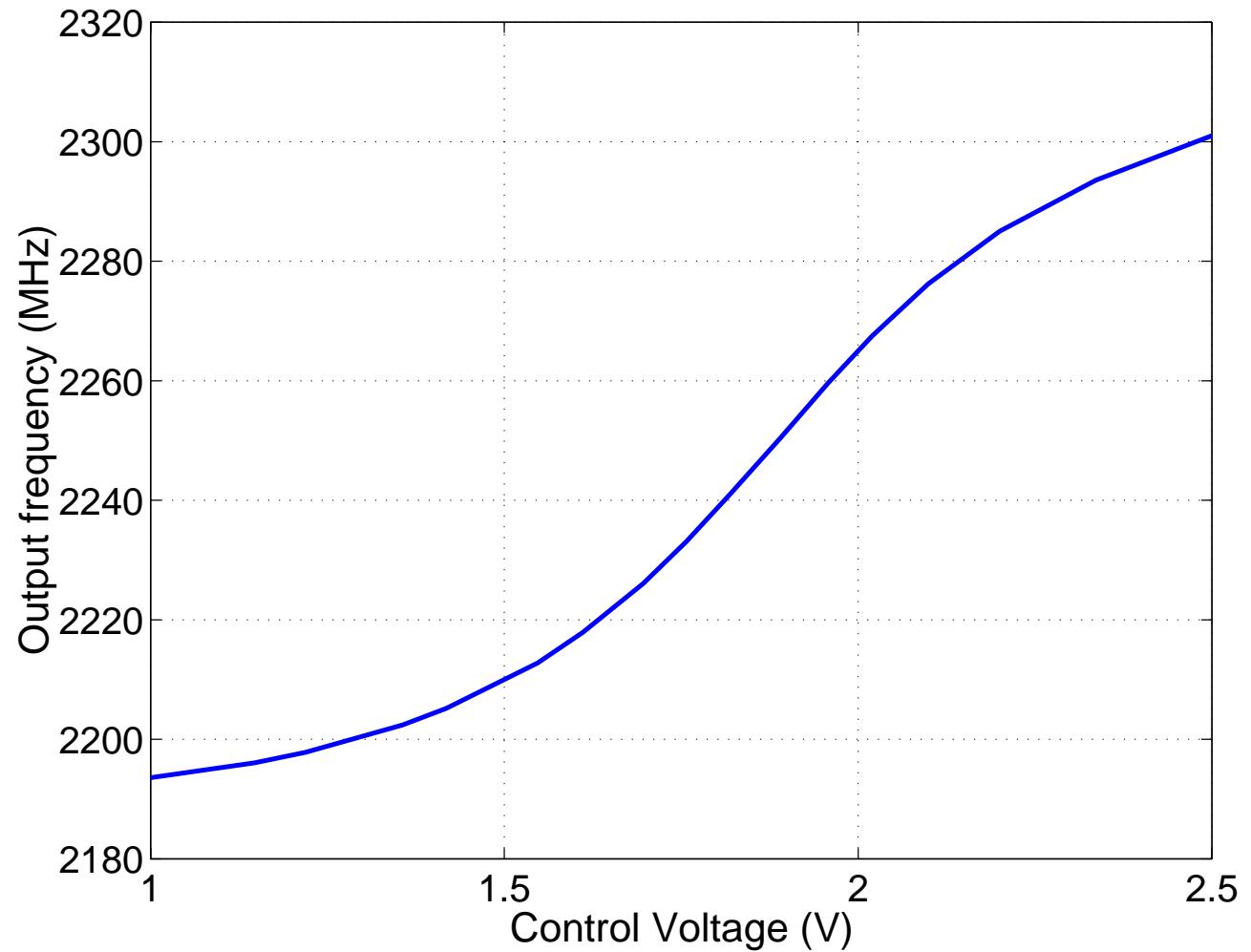
- in planar spiral inductors maximizing L does not maximize LQ



maximize L for a given LQ

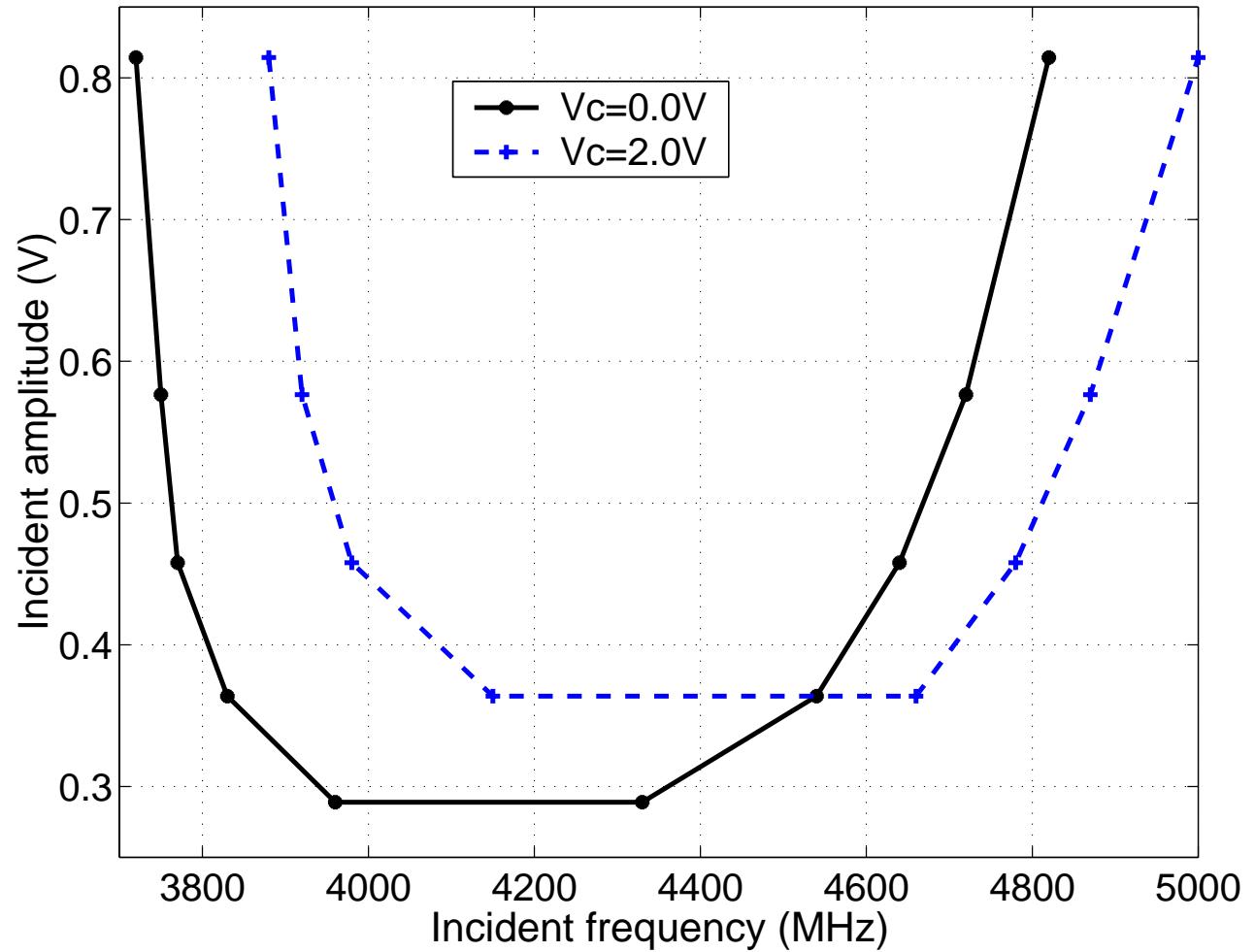
MEASUREMENT (FREE-RUNNING OSCILLATION)

- $0.24\mu\text{m}$ CMOS
- $V_{dd}=2.0\text{V}$
- $I_{bias}=600\mu\text{A}$
- $\Delta f=110\text{MHz}$
- $\frac{\Delta f}{f_o}=5\%$
- $\Delta V_c=1.5\text{V}$

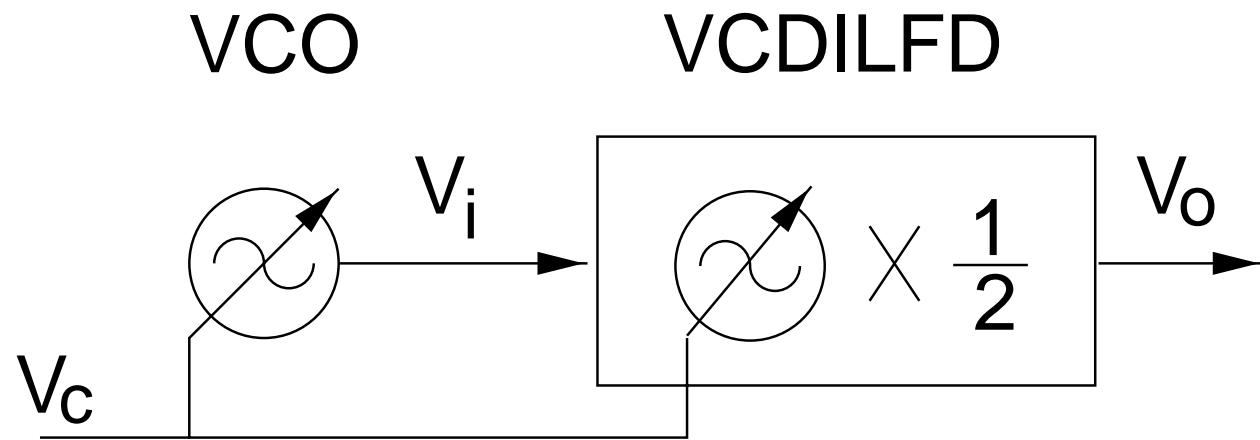


MEASUREMENTS (FREQUENCY RANGE)

- $0.24\mu\text{m}$ CMOS
- $V_{dd}=1.5\text{V}$
- $I_{bias}=300\mu\text{A}$



TRACKING ILFD

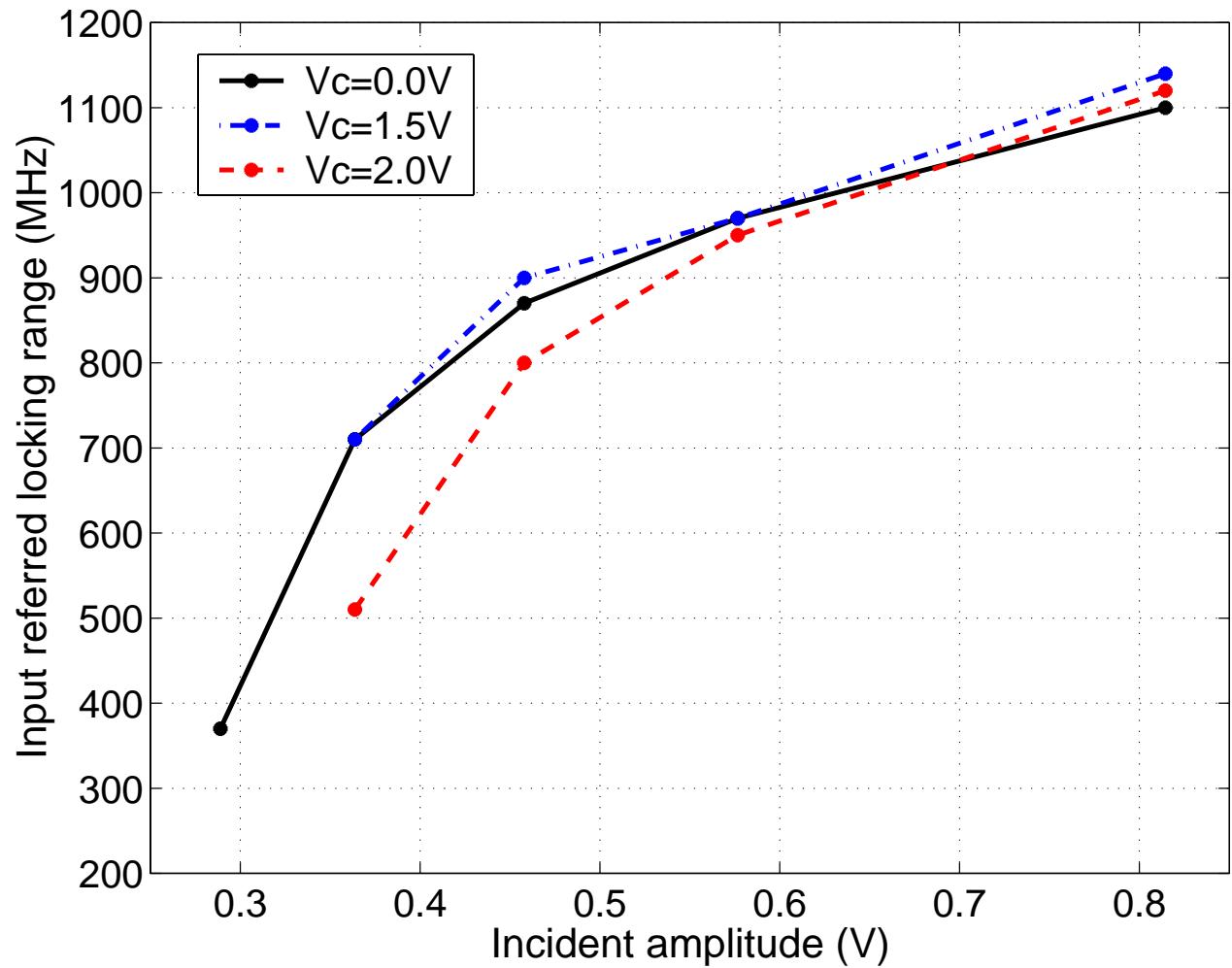


- locking range extension

Rategh *et al.*, symposium on VLSI circuits, June 1999, session 12.1

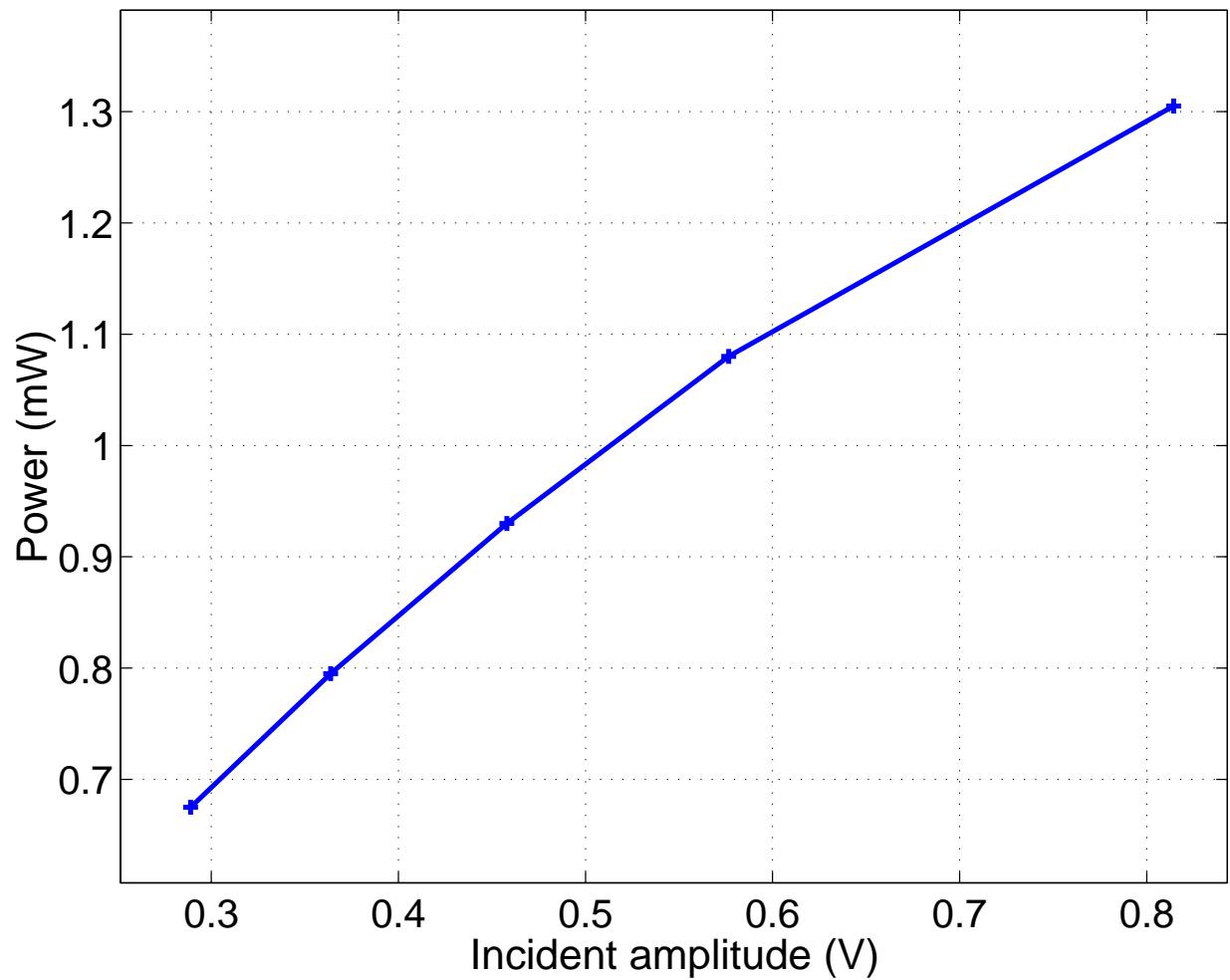
MEASUREMENTS (LOCKING RANGE)

- $0.24\mu\text{m}$ CMOS
- $\text{Vdd}=1.5\text{V}$
- $f_o=2.2\text{GHz}$
- $f_i=4.4\text{GHz}$
- $\Delta f=900\text{MHz}$
 $\approx 20\% @ 0.5\text{V}$

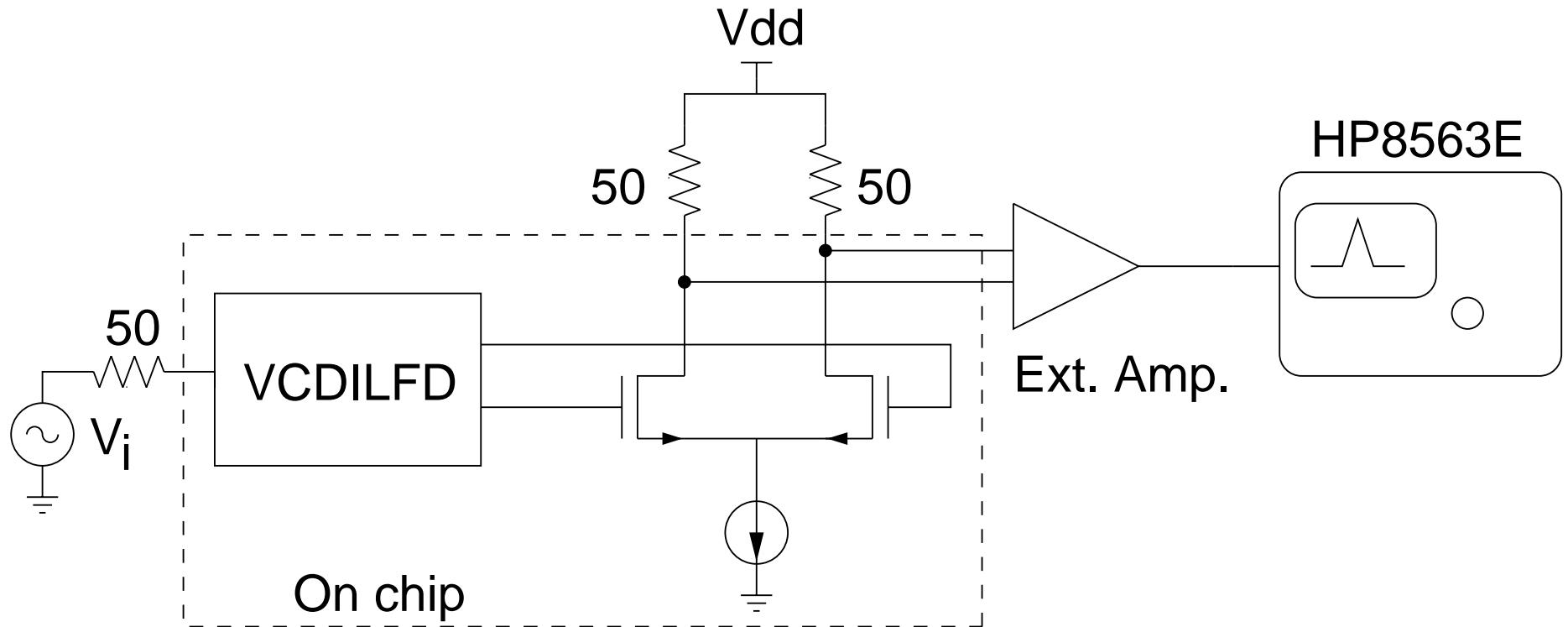


MEASUREMENTS (POWER CONSUMPTION)

- $0.24\mu\text{m}$ CMOS
- $\text{Vdd}=1.5\text{V}$
- $f_o=2.2\text{GHz}$
- $f_i=4.4\text{GHz}$
- $P=1.0\text{mW} @ 0.5\text{V}$

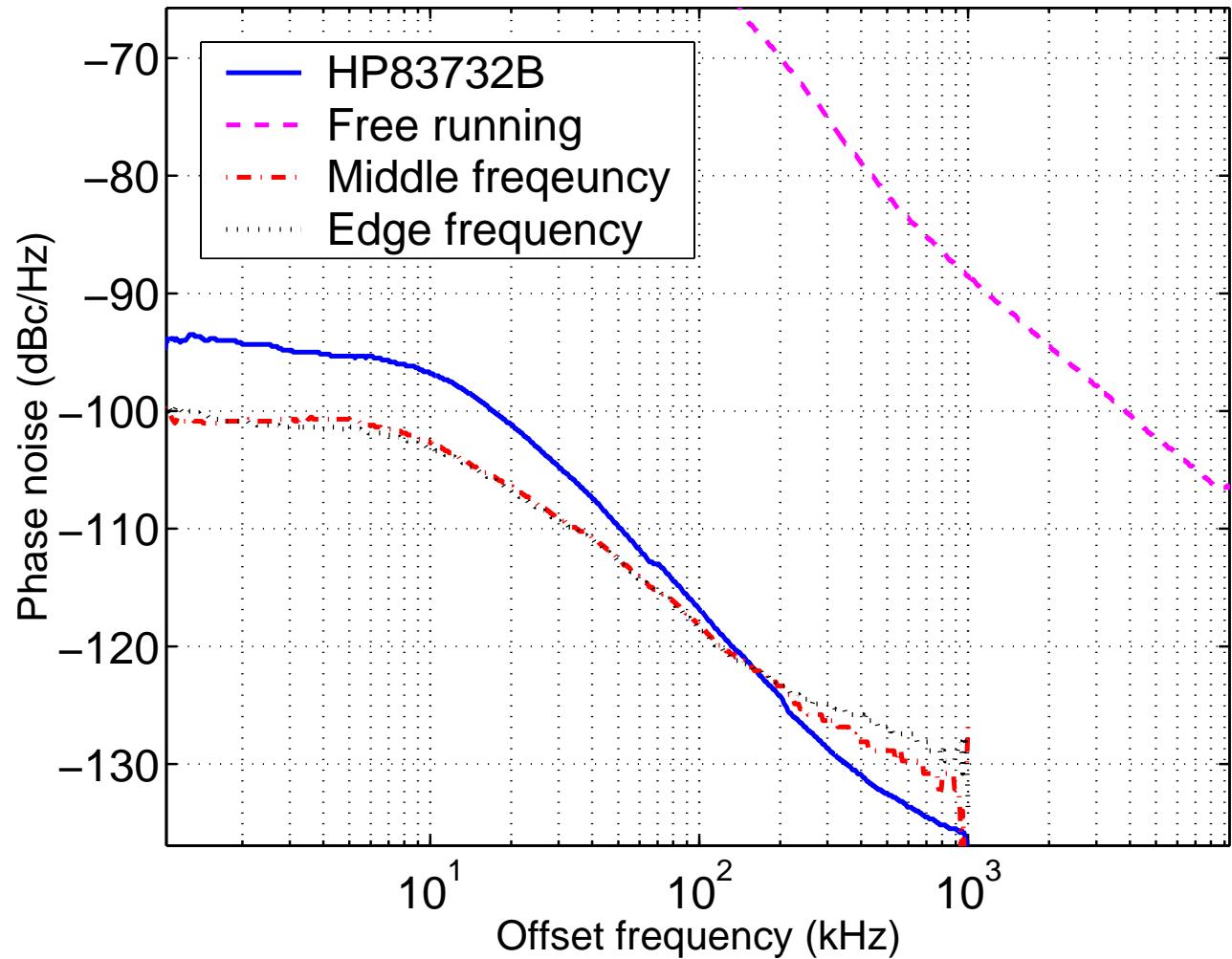


PHASE NOISE MEASUREMENT TEST SETUP



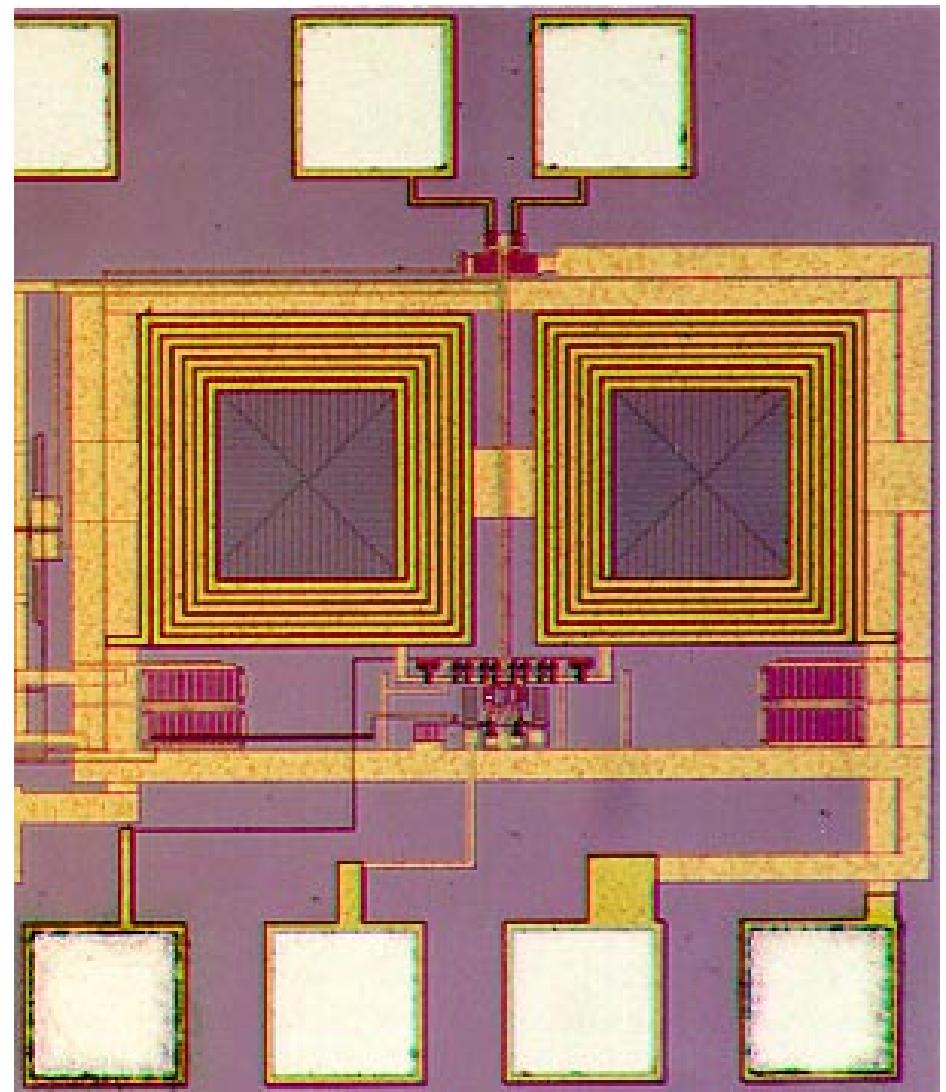
MEASUREMENTS (PHASE NOISE)

- $0.24\mu\text{m}$ CMOS
- $\text{Vdd}=1.5\text{V}$
- $f_o=2.2\text{GHz}$
- $f_i=4.4\text{GHz}$



CHIP MICROGRAPH

- $0.24\mu\text{m}$ CMOS
- area= 0.186mm^2
 $(345\mu\text{m} \times 540\mu\text{m})$



SUMMARY

| | |
|--------------------------------|--|
| maximum frequency of operation | 5GHz |
| output frequency tuning | 110MHz \approx 5% |
| input-referred locking range | 450MHz \approx 10% @ 0.7mW 900MHz \approx 20% @ 1.0mW |
| technology | 0.24μm CMOS |
| die area | 0.186mm ² |

flip-flop-based divider

| | |
|--------------------------|--------------|
| 0.24μm CMOS (simulation) | 7mW @ 5GHz |
| 0.1μm CMOS | 2.6mW @ 5GHz |

(Razavi *et al.*, JSSC Vol. 30, No.2, pp 101–109, Feb. 1995)

CONCLUSION

- injection–locked frequency dividers can be designed with:
 - very large locking range
 - very low power consumption
- spiral inductor design can be optimized to increase the ILFD locking range
- varactors can be used to extend the ILFD locking range (tracking ILFD)
- voltage–controlled ILFDs are suitable for low–power and high–frequency wireless systems

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